



NDT KIT® product line

ULTRASONIC DATA ANALYSIS

ULTIS
is the only UT analysis software
fully compliant with Airbus
requirements

THE ULTRASONIC ANALYSIS SOFTWARE

An innovative software package dedicated to non-destructive testing, ultrasonic data analysis and automated diagnosis.

- ▲ 100% composite oriented
- ▲ compatible with most inspection systems
- ▲ full harmonization of the ultrasonic data analysis process
 - ▲ faster diagnosis
 - ▲ cycle and cost reduction
 - ▲ 100% compliant with AIRBUS requirements
 - ▲ Automated defect detection
 - ▲ Automated reporting

Compatible data formats : M2M, Tecnom, Sonatest, Sepema, Logisonic, Olympus, GE.



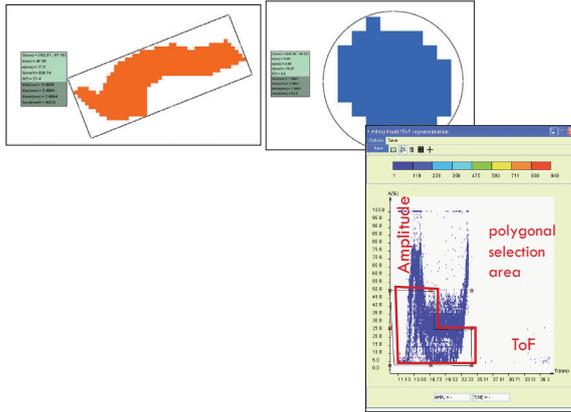
Developed by : **AIRBUS**
GROUP

CONTACT

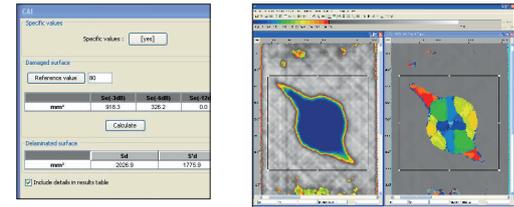
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MEASUREMENT TOOLS



IMPACT CHARACTERIZATION



FEATURES

- **Compatibility with multiple data formats** – 2D ultrasonic A-scan and C-scan
- **Manage C-scan parameters** (% , dB, μ s, mm, plies)
- **Colour palette management:**
 - Palettes with separated colours, linear or versatile step
 - Grayscale or colour palette up to 256 levels
 - Manage the colour of specific pixels (NaN, No echo, deleted, No synchro)
 - Load and adjust pre-defined palettes, create a new palette, modify an existing palette
 - Sliding palette for enhanced resolution over large range
 - Palette standardization for several C-scans
- **Manage A-scan data:**
 - Analysis of A-scan data : create, save and load a configuration (gates definition, choice of the C-scan to be calculated, additional general gain and time corrected gain)
 - Display mode modification (RF, FW, HW+ and HW-)
 - Frequency analysis
 - B-scan and D-scan display and analysis
 - Slicer (C-scan dynamically displayed by slice of material)
- **C-scan data post processing:**
 - C-scan image processing (compression, zoom, modification of origins, duplication, rotation and symmetry, automatic matching, merging, edge effect correction, apply a mathematical formula).
 - Processing tools to create a reference C-scan (synthesis using one or several C-scans)
 - Correction of amplitude
- Create mathematical formulae with C-scans
- **Layout, mask and selection shape:**
 - Create and save mask, layout and selection shapes
 - Create a mask based on a CAD drawing
 - Geometrical and statistical information in the selection shape
 - Assign an acceptance level to a selection shape
- **Configurable statistics tools:**
 - (histogram, specific measurement at predefined positions, drilling control, CAI calculations for impact characterization)
- **Defects detection:**
 - Create a defect detection configuration taking into account acceptance levels: maximum size of acceptable defects calculated according to real surface or to a surrounding shape (rectangular or circular), defect density calculated in circles or along lines
 - Load a predefined configuration
 - Apply defects grouping criteria
 - Manage amplitude/thickness dependant criteria for out of tolerance pixel selection
 - Filter backwall echo to highlight Time of Flight out of tolerance pixels
 - Detection results displayed on the C-scan and in the table of defects (dimensions and position)
- **Automatic analysis and reporting :**
 - Define automatic analysis configuration (batch of actions to be automatically executed on C-scans)
 - Launch a batch of predefined actions, create an automatic report.
 - Customizable report template